

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/773,150	CHEN, TIEN-CHING	
		Examiner	Art Unit	Page 1 of 1
		Victor R. Kostak	2622	

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0212904 A1	10-2004	Sekine et al.	359/819
*	B	US-4,281,895	08-1981	Mohr, Siegfried H.	359/827
*	C	US-5,249,082 A	09-1993	Newman, Peter A.	359/813
*	D	US-6,567,222 B2	05-2003	Shirota, Kei	359/699
*	E	US-5,212,595 A	05-1993	Dennison et al.	359/513
*	F	US-4,957,341	09-1990	Hasegawa, Shinichi	359/819
*	G	US-5,299,067 A	03-1994	Kutz et al.	359/827
*	H	US-5,218,484 A	06-1993	Terai, Takashi	359/823
*	I	US-5,054,886	10-1991	Ozaki et al.	359/823
*	J	US-6,594,089 B2	07-2003	Tanabe et al.	359/703
*	K	US-2004/0125471 A1	07-2004	Chen, Jones	359/811
*	L	US-2003/0128304 A1	07-2003	Park et al.	348/781
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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